

< IGBT MODULES >

CM900DUC-24NF

HIGH POWER SWITCHING USE **INSULATED TYPE**



Maximum junction temperature T_{imax}

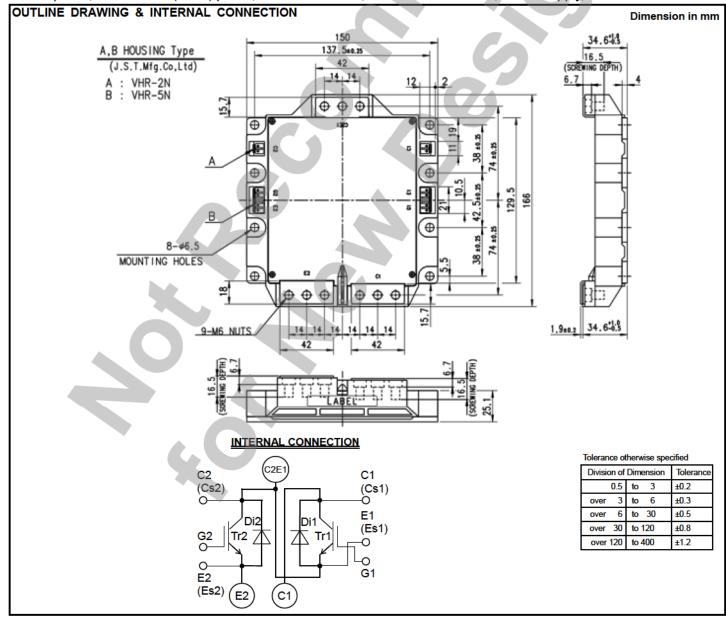
Collector current I_C 900A

Collector-emitter voltage V_{CES} 1 2 0 0 V

- Flat base Type
- Copper base plate (non-plating)
- RoHS Directive compliant
- •Recognized under UL1557, File E323585

APPLICATION

Wind power, Photovoltaic (Solar) power, AC Motor Control, Motion/Servo Control, Power supply, etc.



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MAXIMUM RATINGS (T_i=25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V	
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector current	DC, T _C =96 °C (Note2, 4)	900	_	
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	1800	Α	
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	5950	W	
I _E (Note1)	Emitter current	DC (Note2)	900	_	
I _{ERM} (Note1)	Emilier current	Pulse, Repetitive (Note3)	1800	_ A	
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	2500	V	
T _j	Junction temperature	-	-40 ~ + 150	°C	
T _{stg}	Storage temperature	(Note7)	-40 ~ +125		

ELECTRICAL CHARACTERISTICS (T_i=25 °C, unless otherwise specified)

r-emitter cut-off current iitter leakage current iitter threshold voltage r-emitter saturation voltage coacitance apacitance transfer capacitance arge delay time e delay time	Conditions $V_{\text{CE}} = V_{\text{CES}}, \text{ G-E short-circuited}$ $V_{\text{GE}} = V_{\text{GES}}, \text{ C-E short-circuited}$ $I_{\text{C}} = 90 \text{ mA, } V_{\text{CE}} = 10 \text{ V}$ $I_{\text{C}} = 900 \text{ A, } V_{\text{GE}} = 15 \text{ V} \text{ (Note5)}$ Refer to the figure of test circuit $V_{\text{CE}} = 10 \text{ V, G-E short-circuited}$ $V_{\text{CC}} = 600 \text{ V, I_{\text{C}}} = 900 \text{ A, V_{\text{GE}}} = 15 \text{ V}$ $V_{\text{CC}} = 600 \text{ V, I_{\text{C}}} = 900 \text{ A, V_{\text{GE}}} = \pm 15 \text{ V,}$ $R_{\text{G}} = 0.35 \text{ \Omega, Inductive load}$	T _j =25 °C T _j =125 °C	Min 6	Typ 7 1.8 2.0 4800	Max. 1.0 1.0 8 2.5 - 140 16 3.0	Uniti mA μA V nF
itter leakage current itter threshold voltage r-emitter saturation voltage pacitance apacitance transfer capacitance arge delay time e delay time	$\begin{split} &V_{\text{GE}}\text{=}V_{\text{GES}}, \text{ C-E short-circuited} \\ &I_{\text{C}}\text{=}90 \text{ mA}, V_{\text{CE}}\text{=}10 \text{ V} \\ &I_{\text{C}}\text{=}900 \text{ A}, V_{\text{GE}}\text{=}15 \text{ V} \\ &\text{Refer to the figure of test circuit} \\ &V_{\text{CE}}\text{=}10 \text{ V}, \text{ G-E short-circuited} \\ &V_{\text{CC}}\text{=}600 \text{ V}, I_{\text{C}}\text{=}900 \text{ A}, V_{\text{GE}}\text{=}15 \text{ V} \\ &V_{\text{CC}}\text{=}600 \text{ V}, I_{\text{C}}\text{=}900 \text{ A}, V_{\text{GE}}\text{=}\pm15 \text{ V}, \end{split}$		7	1.8 2.0 - -	1.0 8 2.5 - 140 16	μA V V nF
itter threshold voltage r-emitter saturation voltage pacitance apacitance transfer capacitance arge delay time e delay time	$I_{C}=90 \text{ mA, } V_{CE}=10 \text{ V}$ $I_{C}=900 \text{ A, } V_{GE}=15 \text{ V} \qquad \text{(Note5)}$ Refer to the figure of test circuit $V_{CE}=10 \text{ V, G-E short-circuited}$ $V_{CC}=600 \text{ V, } I_{C}=900 \text{ A, } V_{GE}=15 \text{ V}$ $V_{CC}=600 \text{ V, } I_{C}=900 \text{ A, } V_{GE}=\pm15 \text{ V,}$		7	1.8 2.0 - -	8 2.5 - 140 16	V V nF
r-emitter saturation voltage pacitance apacitance transfer capacitance arge delay time e delay time	I _C =900 A, V _{GE} =15 V (Note5) Refer to the figure of test circuit $V_{CE}=10 \text{ V, G-E short-circuited}$ $V_{CC}=600 \text{ V, I}_{C}=900 \text{ A, V}_{GE}=15 \text{ V}$ $V_{CC}=600 \text{ V, I}_{C}=900 \text{ A, V}_{GE}=\pm15 \text{ V,}$		7	1.8 2.0 - -	2.5 - 140 16	V
pacitance apacitance transfer capacitance arge delay time e delay time	Refer to the figure of test circuit $V_{\text{CE}}=10 \text{ V, G-E short-circuited}$ $V_{\text{CC}}=600 \text{ V, I}_{\text{C}}=900 \text{ A, V}_{\text{GE}}=15 \text{ V}$ $V_{\text{CC}}=600 \text{ V, I}_{\text{C}}=900 \text{ A, V}_{\text{GE}}=\pm15 \text{ V,}$		- - - - -	2.0 - -	- 140 16	nF
pacitance apacitance transfer capacitance arge delay time e delay time	V_{CE} =10 V, G-E short-circuited V_{CC} =600 V, I_{C} =900 A, V_{GE} =15 V V_{CC} =600 V, I_{C} =900 A, V_{GE} =±15 V,	T _j =125 °C	- - -	-	16	nF
apacitance transfer capacitance arge delay time e delay time	V_{cc} =600 V, I_{c} =900 A, V_{GE} =15 V V_{cc} =600 V, I_{c} =900 A, V_{GE} =±15 V,		-	- - - 4800	16	
transfer capacitance arge delay time e delay time	V_{cc} =600 V, I_{c} =900 A, V_{GE} =15 V V_{cc} =600 V, I_{c} =900 A, V_{GE} =±15 V,	X	- - -	- - 4800		<u> </u>
arge delay time e delay time	V_{cc} =600 V, I_c =900 A, V_{GE} =±15 V,		- - -	4800	3.0	0
delay time e delay time	V_{cc} =600 V, I_c =900 A, V_{GE} =±15 V,		-	4800	_	0
e delay time			-			nC
delay time				-	600	
	R _G =0.35 Ω, Inductive load		-	-	200]
	R _G =0.35 Ω, inductive load		-	-	800	ns
			-	-	300	00
collector voltage	I _E =900 A, G-E short-circuited, Refer to the figure of test circuit	T _j =25 °C	-	2.5	3.2	V
(Note.1) Emitter-collector voltage	(Note5)	T _j =125 °C	-	2.1	-	
recovery time	V _{CC} =600 V, I _E =900 A, V _{GE} =±15 V,		-	-	500	ns
recovery charge	R _G =0.35 Ω, Inductive load		-	50	-	μC
switching energy per pulse	V _{CC} =600 V, I _C =I _E =900 A,		-	147.5	-	
switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, R_{G}=0.35 \Omega, T_{j}=125 ^{\circ}\text{C},$		-	88	-	m.
recovery energy per pulse	Inductive load		-	91.8	-	mJ
lead resistance	Main terminals-chip, per switch,		-	0.286	-	mΩ
nate resistance				1.0	_	Ω
	recovery time recovery charge switching energy per pulse switching energy per pulse recovery energy per pulse lead resistance gate resistance	recovery charge R_G =0.35 Ω , Inductive load N_G =0.35 N_G , Inductive load N_G =0.35 N_G , Inductive load N_G =15 N_G =15 N_G =16 N_G =17 N_G =18 N_G =17 N_G =18 N_G =18 N_G =19 N_G =	recovery charge R_G =0.35 Ω , Inductive load V_{CC} =600 V , I_C = I_E =900 A , V_G =±15 V , R_G =0.35 Ω , T_j =125 °C, Inductive load Main terminals-chip, per switch, T_C =25 °C (Note4) Per switch	recovery charge $R_G=0.35~\Omega$, Inductive load $-$ switching energy per pulse $V_{CC}=600~V$, $I_C=I_E=900~A$, $-$ switching energy per pulse $V_{GE}=\pm15~V$, $R_G=0.35~\Omega$, $T_j=125~^{\circ}C$, $-$ recovery energy per pulse $-$ Inductive load $-$ Main terminals-chip, per switch, $ -$ gate resistance $-$ Per switch $ -$ Per switch $ -$	recovery charge $R_G=0.35~\Omega$, Inductive load -50 switching energy per pulse $V_{CC}=600~V$, $I_{C}=I_{E}=900~A$, -147.5 switching energy per pulse $V_{GE}=\pm15~V$, $R_G=0.35~\Omega$, $T_j=125~C$, -88 recovery energy per pulse Inductive load -91.8 Main terminals-chip, per switch, $T_{C}=25~C$ (Note4) -286 gate resistance Per switch -1.0	recovery charge $R_G=0.35~\Omega$, Inductive load -50 - switching energy per pulse $V_{CC}=600~V$, $I_{C}=I_{E}=900~A$, -147.5 - switching energy per pulse $V_{GE}=\pm15~V$, $R_G=0.35~\Omega$, $T_J=125~^{\circ}C$, -88 - recovery energy per pulse Inductive load -91.8 - Main terminals-chip, per switch, $T_{C}=25~^{\circ}C$ (Note4) -0.286 - gate resistance Per switch -1.0 -

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THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Lluid
			Min.	Typ.	Max.	Unit
R _{th(j-c)Q}	The second second second	Junction to case, per Inverter IGBT (Note4)	929	-	21	IZUANI
R _{th(j-c)D}	Thermal resistance	Junction to case, per Inverter DIODE (Note4)	i.e.s	-	34	K/kW
R _{th(c-s)}	Contact thermal resistance	Case to heat sink, per 1/2 module, Thermal grease applied (Note4, 6)	-	12	-	K/kW

MECHANICAL CHARACTERISTICS

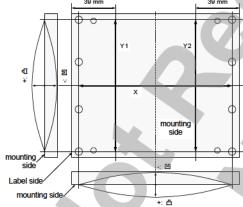
Symbol	Item	Conditions	Limits			Unit
		Conditions	Min.	Тур.	Max.	Onit
Mt	Mounting torque	Main terminals M 6 screw	3.5	4.0	4.5	N⋅m
Ms		Mounting to heat sink M 6 screw	3.5	4.0	4.5	N⋅m
ds	Creepage distance	Terminal to terminal	24	-	-	mm
		Terminal to base plate	33	-	-	
d _a Clearance	Clearance	Terminal to terminal	14	-	-	mm
	Clearance	Terminal to base plate	33	-	-	mm
m	mass	-		1450	-	g
ec	Flatness of base plate	On the centerline X, Y1, Y2 (Note8)	-50	-	+100	μm

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free wheeling diode (DIODE).

- 2. Junction temperature (T_i) should not increase beyond T_{imax} rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating.
- Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

The heat sink thermal resistance should measure just under the chips.

- 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
- 6. Typical value is measured by using thermally conductive grease of λ=0.9 W/(m·K).
- 7: The operation temperature is restrained by the permission temperature of female connector housing.
- 8. Base plate (mounting side) flatness measurement points (X, Y1 and Y2) are as follows of the following figure.



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HIGH POWER SWITCHING USE

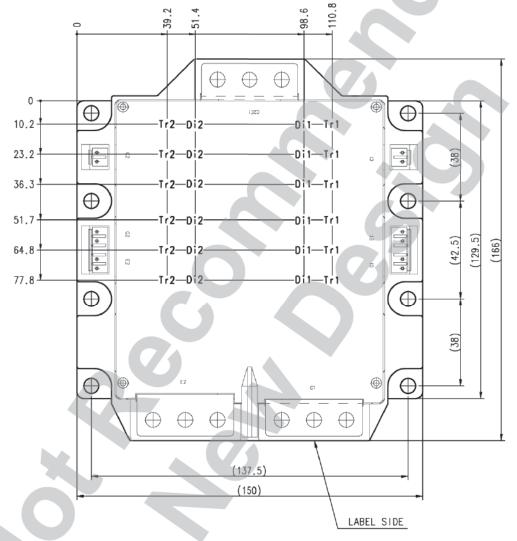
INSULATED TYPE

RECOMMENDED OPERATING CONDITIONS

Symbol	Item	Conditions	Limits			Unit
Syllibol	item	Conditions	Min.	Тур.	Max.	Offic
Vcc	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	800	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	0.35	-	2.2	Ω

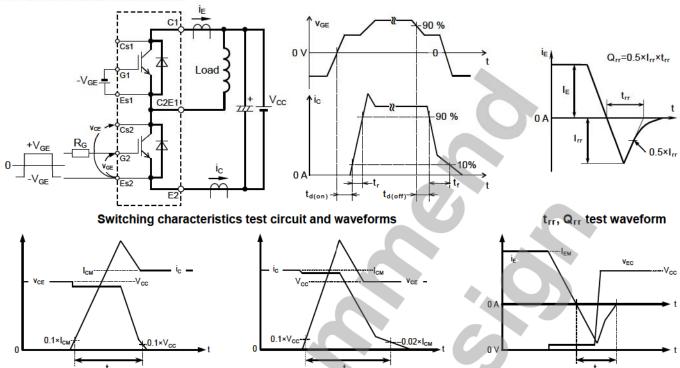
CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm



Tr1/Tr2: IGBT, Di1/Di2: DIODE

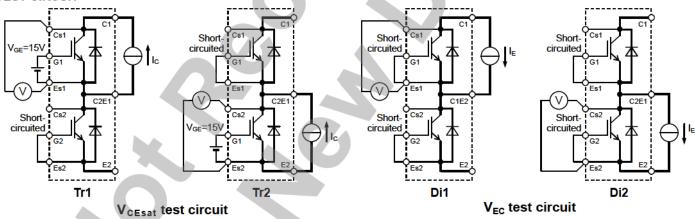
TEST CIRCUIT AND WAVEFORMS



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

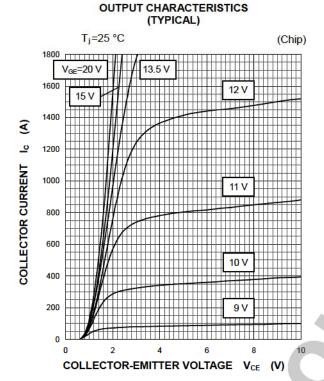


IGBT Turn-on switching energy

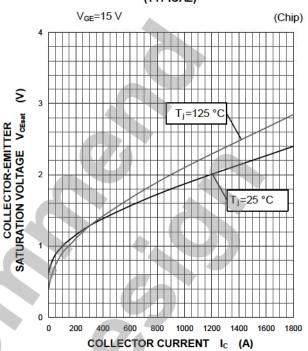


DIODE Reverse recovery energy

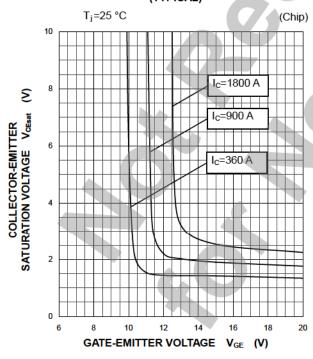
PERFORMANCE CURVES



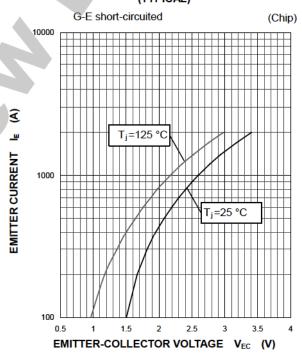
COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



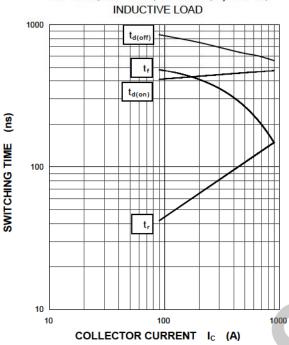
FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)



PERFORMANCE CURVES

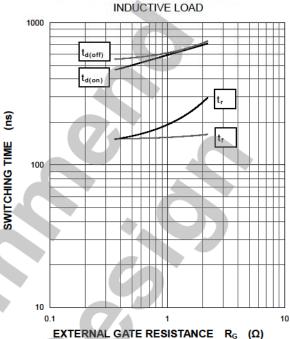
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 $V_{CC}\text{=}600$ V, $V_{GE}\text{=}\pm15$ V, $R_{G}\text{=}0.35~\Omega,\,T_{j}\text{=}125~^{\circ}\text{C},$



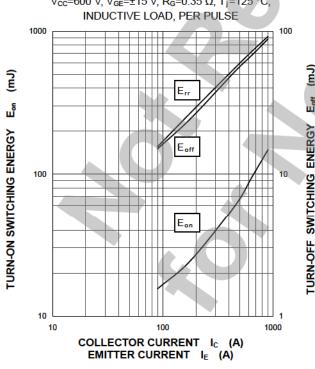
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600 V, I_{C} =900 A, V_{GE} =±15 V, T_{j} =125 °C,



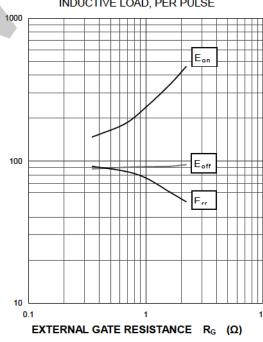
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600 V, V_{GE} =±15 V, R_{G} =0.35 Ω , T_{j} =125 °C,



HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

 V_{CC} =600 V, I_C/I_E =900 A, V_{GE} =±15 V, T_j =125 °C, INDUCTIVE LOAD, PER PULSE



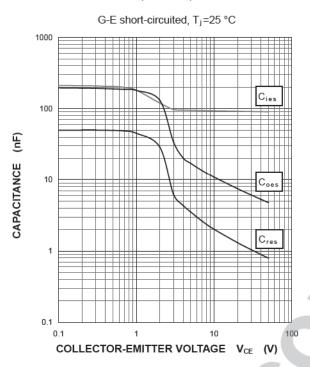
SWITCHING ENERGY (mJ)
REVERSE RECOVERY ENERGY (mJ)

REVERSE RECOVERY ENERGY

INSULATED TYPE

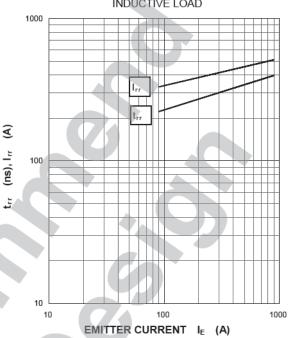
PERFORMANCE CURVES

CAPACITANCE CHARACTERISTICS (TYPICAL)

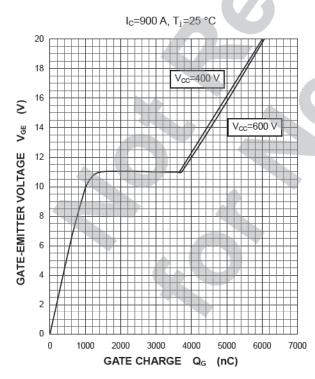


FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)

 V_{CC} =600 V, V_{GE} =±15 V, R_{G} =0.35 Ω , T_{j} =25 °C, INDUCTIVE LOAD

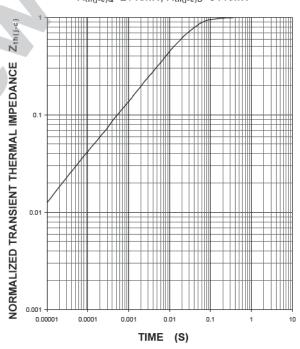


GATE CHARGE CHARACTERISTICS (TYPICAL)



TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)

Single pulse, $T_c=25$ °C $R_{th(j-c)Q}=21$ K/kW, $R_{th(j-c)D}=34$ K/kW



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